

Quarterly Reliability Monitoring Results

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier	User Part Number					
Nexperia B.V.	PMST4401					
Name of Laboratory	Part Description					
Assembly reliability labs	Nexperia DHAM SMD package		Small Signal Bipolar Transistor			
Based on AEC-Q101 Test	Test Conditions	Duration	# Lots	# Quantity	# Rejects	
# E1	TEST Pre- and Post-Stress Electrical Test Tamb = 25 °C	N/A	see below	all parts	see below	
# A1	PC Preconditioning JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	1265	69890	0	
# B1	HTRB High Temperature Reverse Bias MIL-STD-750-1 M1039 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	1000 hours	316	18920	0	
# A4	TC Temperature Cycling JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000 cycles	260	15680	0	
# A3 or	UHAST Unbiased HAST JESD22-A118 Tamb = 130 °C, RH = 85 %	96 hours	270	16360	0	
# A3 alt	AC Autoclave JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)					
# A2 alt	H3TRB High Humidity High Temperature Reverse Bias JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage ^[1]	1000 hours	262	15760	0	
# A5	IOL Intermittent Operating Life MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj = 100 °C for 15000 cycles	1000 hours	262	15760	0	
# C8	RSH Resistance to Solder Heat JESD22-A111 260 °C ± 5 °C	10 s	211	6330	0	
# C10	SD Solderability J-STD-002		468	4680	0	

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Small Signal Bipolar Transistor	18920	0	0,22	4,46E+09

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